

高密度磁気記録用薄膜磁気テープの開発

Development of Thin Film Media for High

稲生 俊雄
加藤 芳雄

Density Magnetic Recording Systems 府川 信一
近藤 昭夫

Toshio INASE

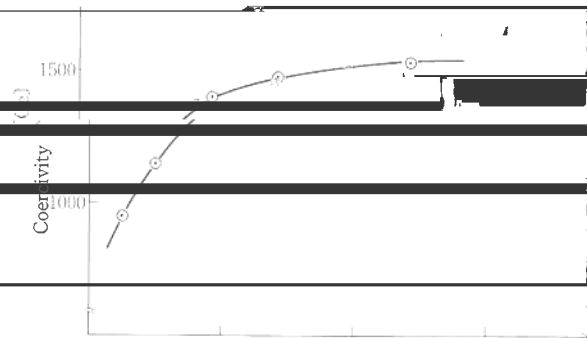
Eiji KATO

Shinichi FUKAWA

Akio KONDO

The table contains data for TOSOT (Total Organic Solvent Oxidation Test) performed on Vet. 94, N. 1 in 1990. The table is mostly obscured by heavy horizontal black bars. Visible text includes the word "W" in several columns, and some numbers like "00" and "11" in the lower half of the page. The table structure appears to have multiple columns and rows, with some data points visible in the lower section.

Lubricant layer

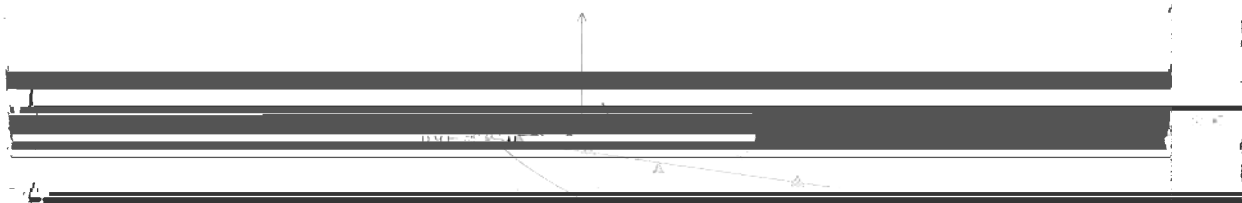


形変換装置は、ニッケルノボラ田、イリジウム、

Under layer (Cu)

(Al alloy)

膜構造は、走査型電子顕微鏡 (SEM) X線回折を用いて



膜のよみか構造で成膜する際、甘塩溶液 暗黒

150 [°C]

10 [mtorr]

Sputter Rate * Thickness (nm·T)

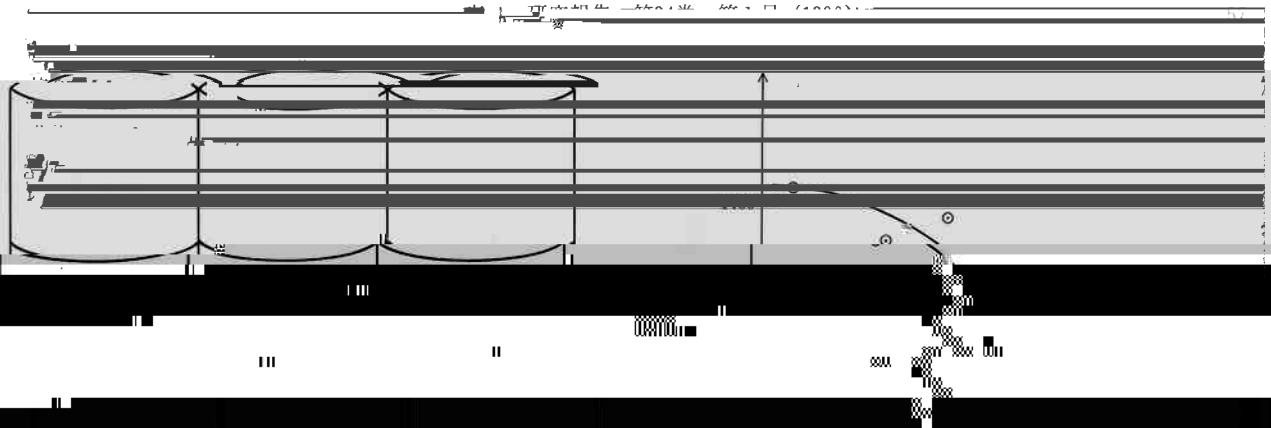
Sputter Rate 2 [A/S] 3 [A/S]

10KV 80 0KX 125n

Substrate bias voltage

Thickness of CoNiCr layer (Å)



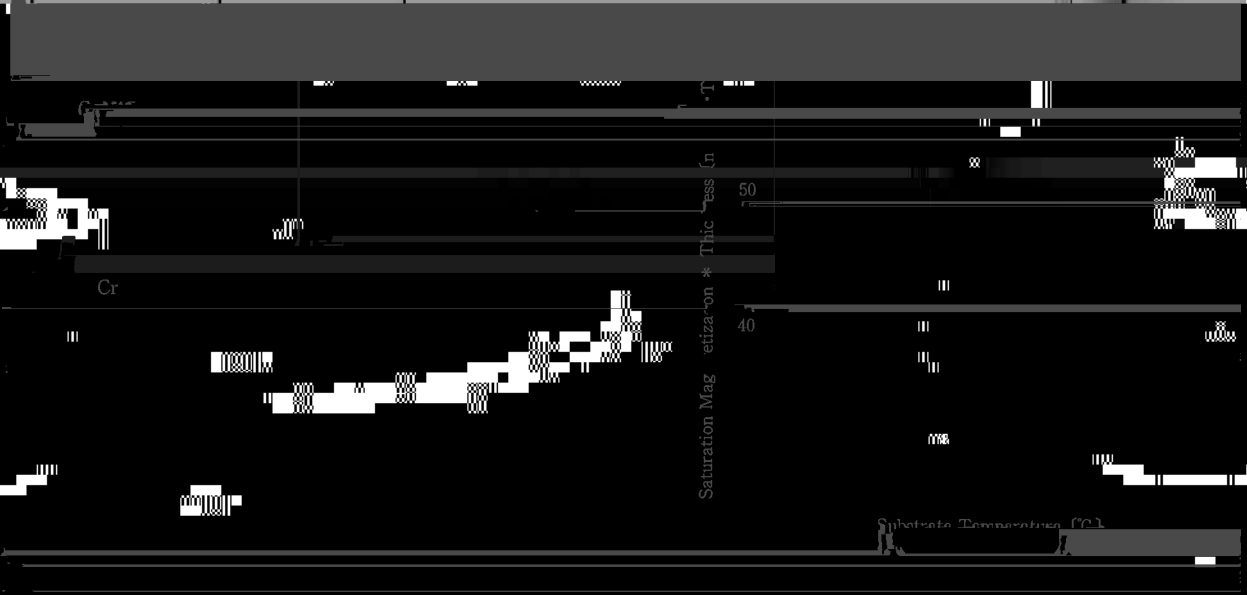


CoNiCr

Coercivity [Oe]

Cr

100 200



Cr

Saturation Magnetization * Thickness [mT]

Saturation Temperature [K]

CoNiCr

(b)

Squareness Ratio

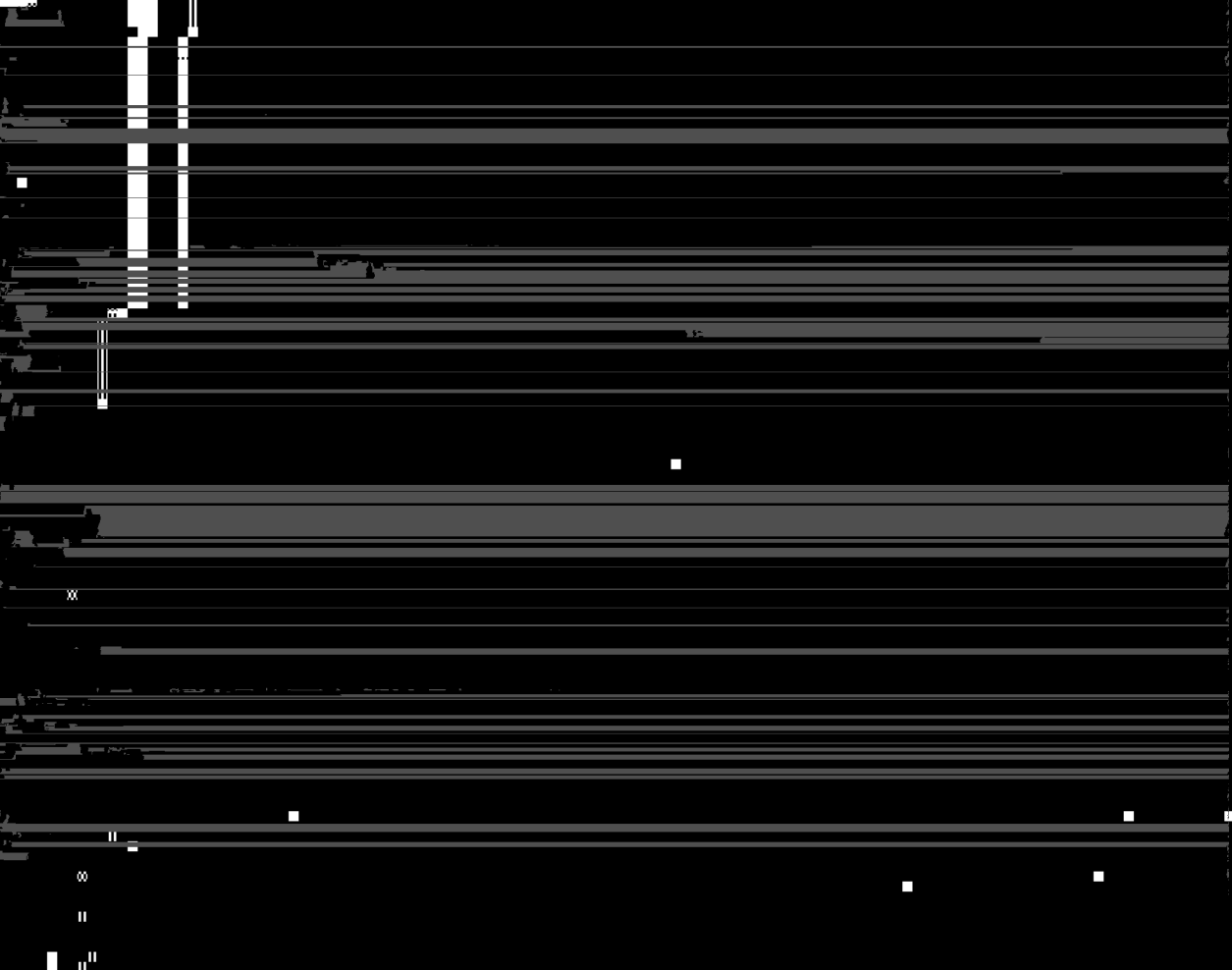
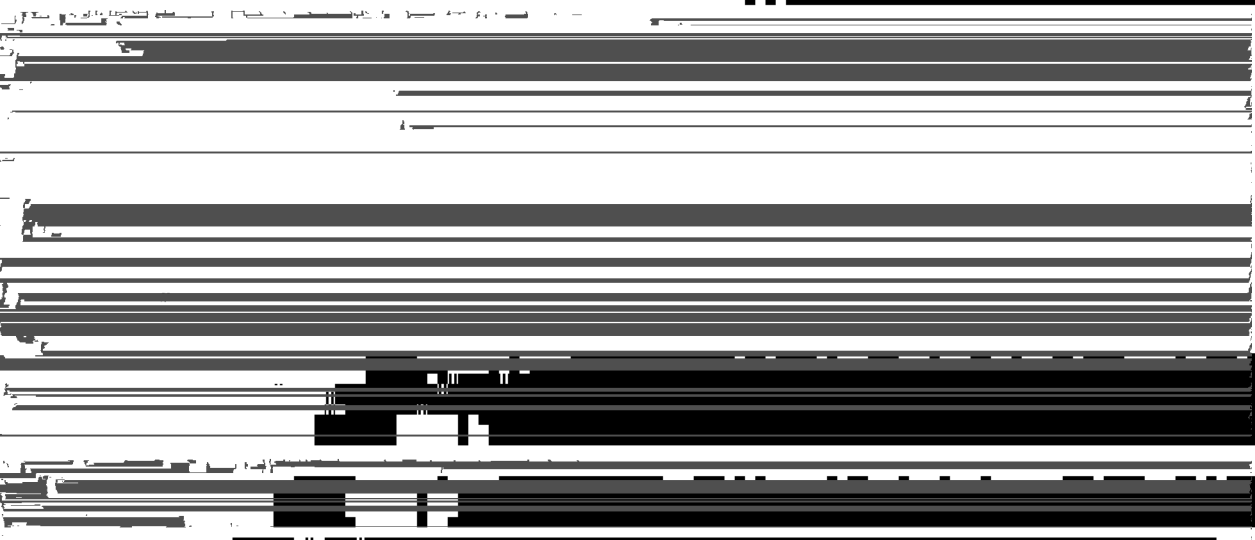
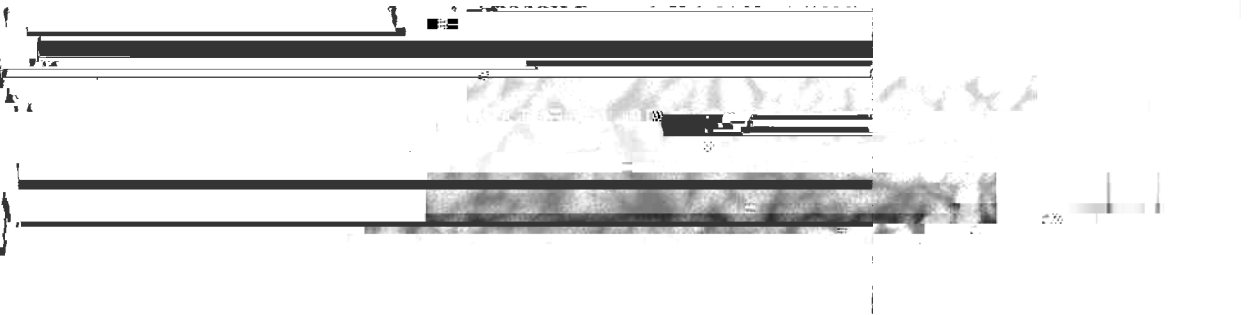


Table 3. The Conditions of Substrate Bias Experiment

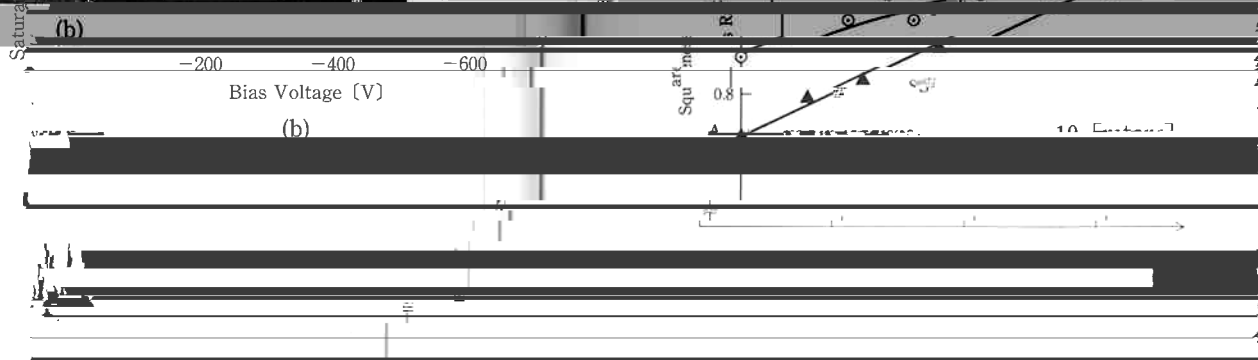
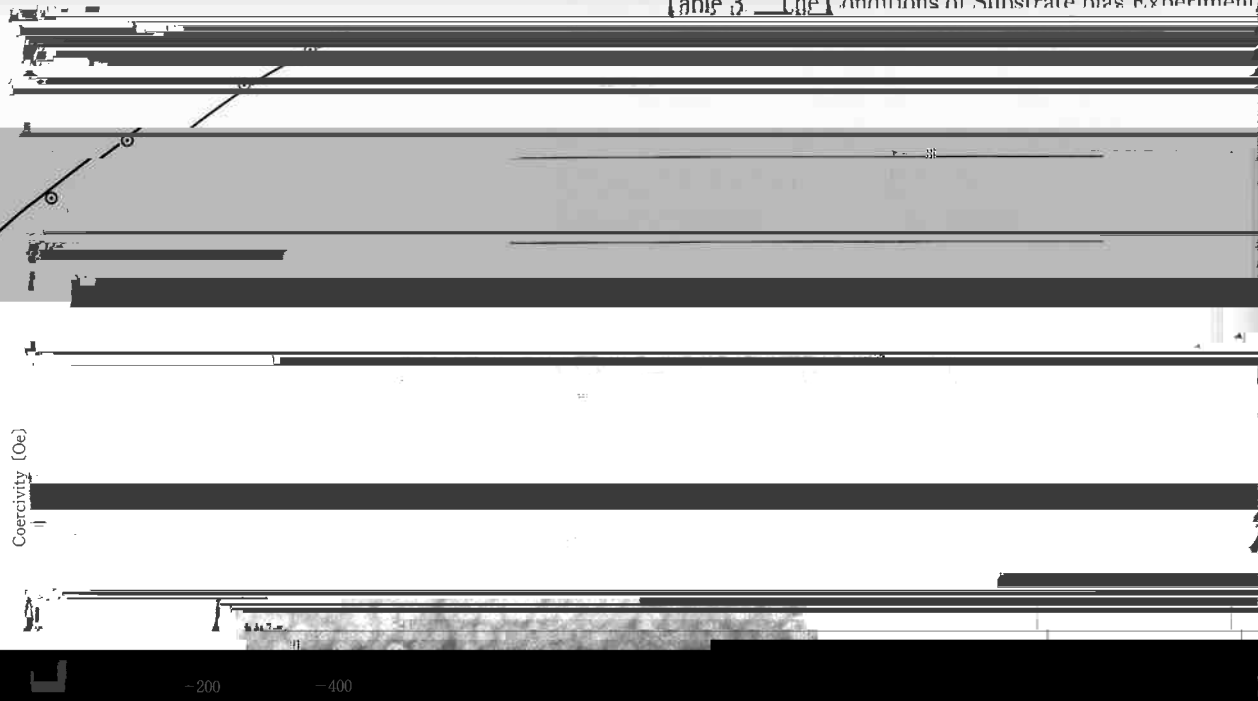


Fig. 10. SEM surface micrographs of the film at

Thickness 2000 [Å] 450 [Å]

Magnetron

Sat

0

15

Cr

Substrate bias voltage -500 [V]

Magnetic

Cr

5

10

15

Sputtered Particle

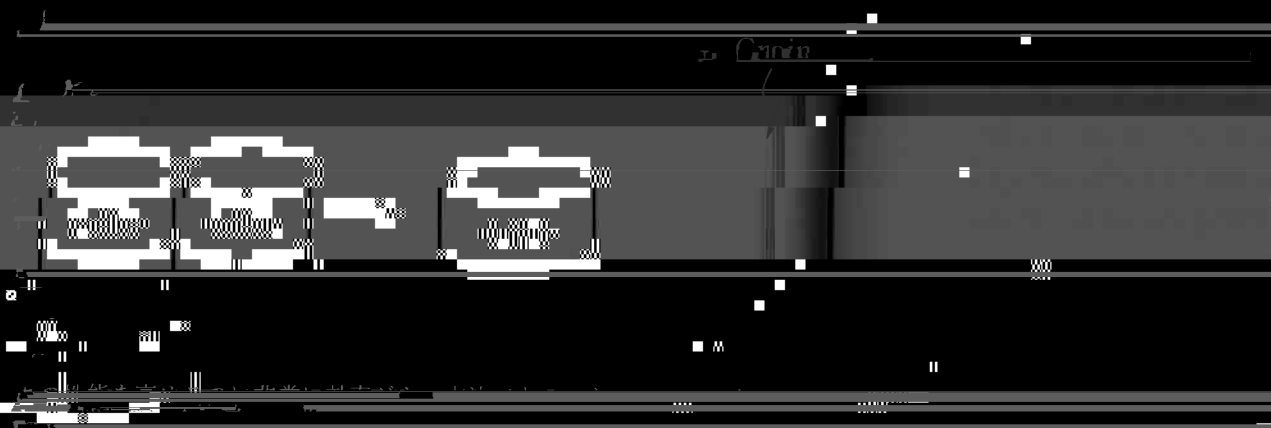
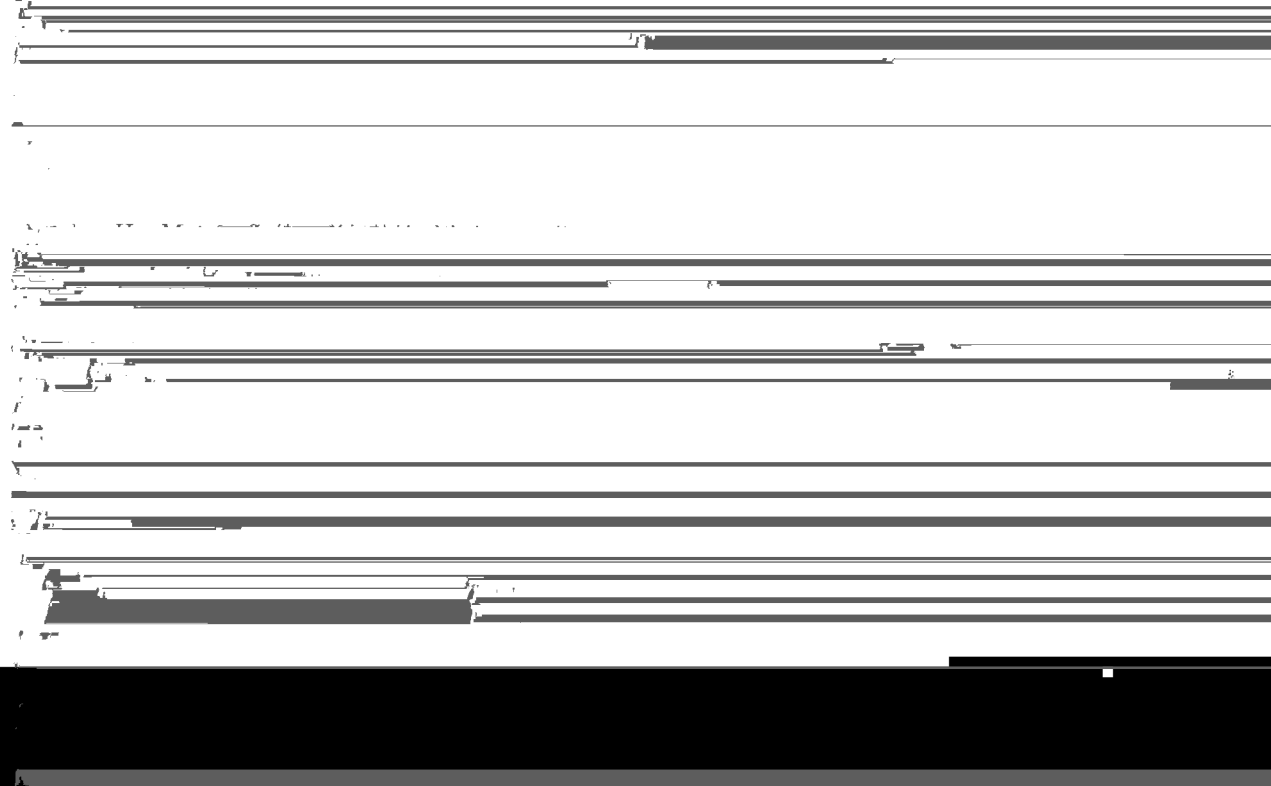
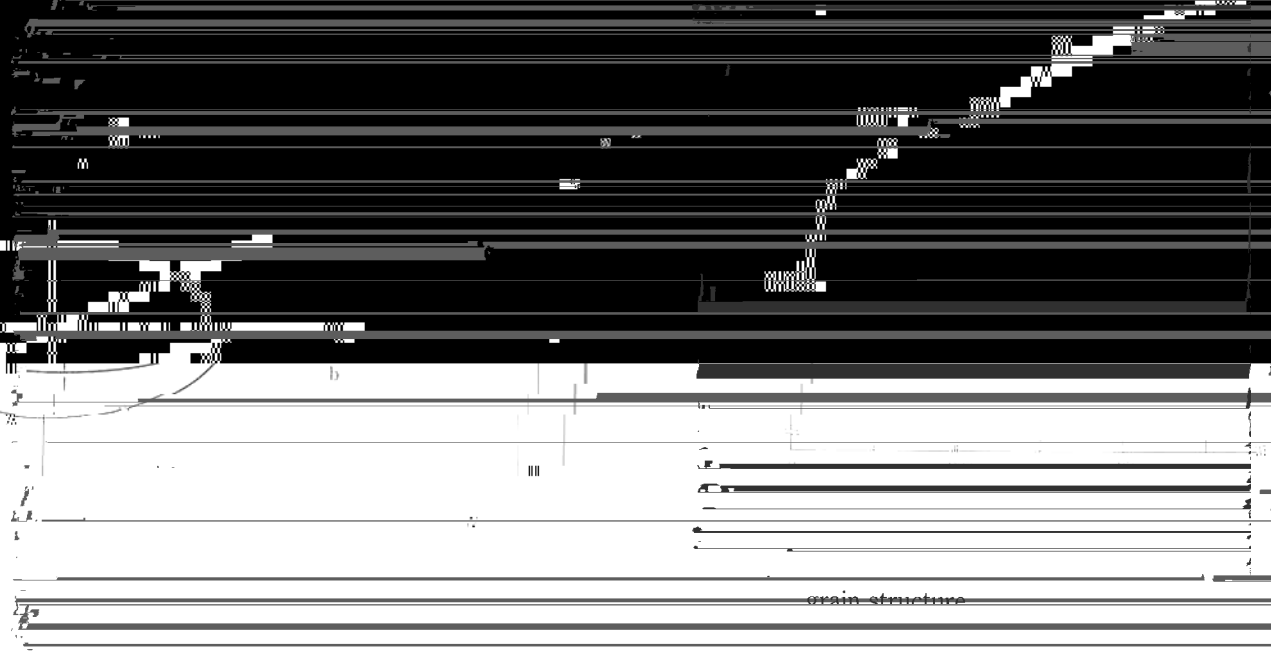
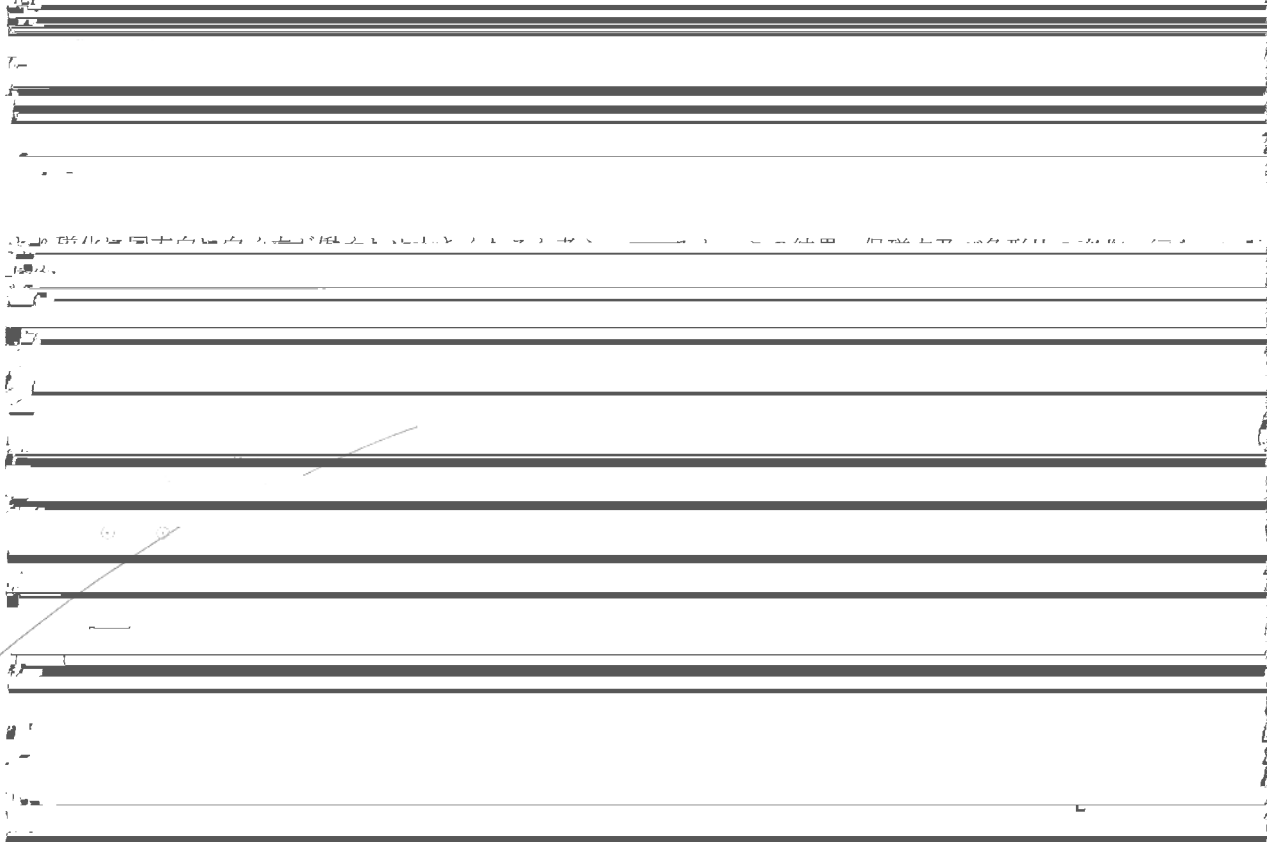


Fig. 45

Fig. 45. Calculated grain structure



grain structure



600 700 800

Diameter of grain [Å]

